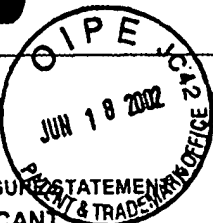


FORM PTO-1449
US Department of Commerce
Patent and Trademark Office



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10/152,743

10/152,743

INFORMATION DISCLOSURE STATEMENT
BY APPLICANT

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Filing Date
5/22/02


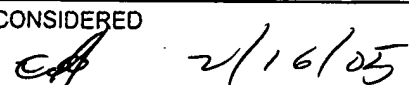
Group Art Unit
Not yet assigned

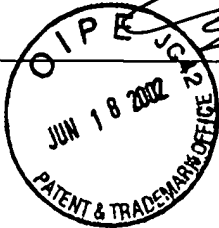
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EXAMINER INITIAL	X	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
dlh	A1	4,553,238	11/12/85	Shaw <i>et al.</i>	372	6	09/30/83
	A2	4,713,822	12/15/87	Lee	372	69	05/24/85
	A3	5,048,026	09/10/91	Shaw <i>et al.</i>	372	6	05/04/88
	A4	5,086,433	02/04/92	Pochelle <i>et al.</i>	372	72	06/12/90
	A5	5,172,388	12/15/92	Long <i>et al.</i>	372	70	07/23/91
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							YES	NO
dlh	B1	EP 0136871 A2	11/12/85	Europe				X
	B2	EP 0403382 A2	05/07/85	Europe				X
	B3	EP 0657070 A1	12/08/94	Europe				X
	B4	EP 0821453 A2	07/18/97	Europe				X
	B5							X
	B6							X
	B7							X
								X

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↑	C2	C. Honninger, et al.; <i>Diode-Pumped Thin-Disk Yb: YAG Regenerative Amplifier</i> ; APPLIED PHYSICS B, pp. 423-426
↓	C3	Steven Jackel, et al.; <i>High-Energy Nd:Dr:GSGG Lasers Based on Phase and Polarization Conjugated Multiple-Pass Amplifiers</i> ; OPTICAL ENGINEERING, Vol. 36, No. 7, July 1997, pp. 2031-2036
↓	C4	K. F. Wall, et al.; <i>A Ti:Al₂O₃ Master-Oscillator/Power-Amplifier System</i> ; IEEE JOURNAL OF QUANTUM ELECTRONICS, June 1993, No. 6, pp. 1505-1514
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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-213002	Application No. 10/806496
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Peter J. de Groot et al.	
		Filing Date March 22, 2004	Group Art Unit 2877

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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	


Examiner Signature 	Date Considered 2/16/05
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-213001	Application No. 10/190,353
		Applicant Peter de Groot et al.	
	Filing Date July 3, 2002	Group Art Unit 2877	

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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>sk</i>	AA	6,195,168	2/27/2001	De Lega et al.	356	497	
	AB	6,154,279	11/28/2000	Thayer	356	376	
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	AI						

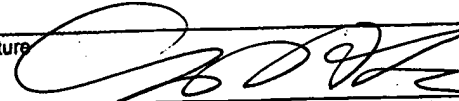
Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
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Examiner Initial	Desig. ID	Document
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	AT	Li et al., "Imaging needle for optical coherence tomography", <u>Optics Letters</u> , Vol. 25, No. 20, pp. 1520-1522 (October 15, 2000)

Examiner Signature 	Date Considered 2/16/05
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	

Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-213001	Application No. 10/190,353
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Peter de Groot et al.	
		Filing Date July 3, 2002	Group Art Unit 2877

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✓	BC	Schwider, "White-light Fizeau interferometer", <u>Applied Optics</u> , Vol. 36, No. 7, pp. 1433-1437 (March 1, 1997)
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Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-213001	Application No. 10/190,353
	Applicant Peter de Groot et al.		
	Filing Date July 3, 2002	Group Art Unit 2877	

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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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	AC						
	AD						
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Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
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	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
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